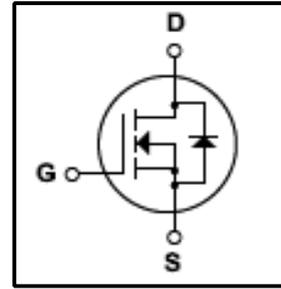


Silicon N-Channel MOSFET

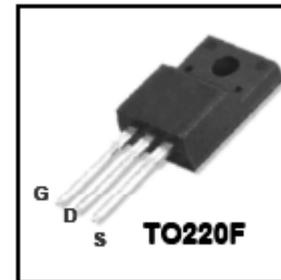
Features

- 2A,600V, $R_{DS(on)}$ (Max 5Ω)@ $V_{GS}=10V$
- Ultra-low Gate Charge(Typical 9.0nC)
- Fast Switching Capability
- 100%Avalanche Tested
- Isolation Voltage ($V_{ISO} = 4000V AC$)
- Maximum Junction Temperature Range(150°C)



General Description

This Power MOSFET is produced using Winsemi's advanced planar stripe, VDMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. This devices is specially well suited for high efficiency switch mode power supply.



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain Source Voltage	600	V
I_D	Continuous Drain Current(@Tc=25°C)	2.0*	A
	Continuous Drain Current(@Tc=100°C)	1.5*	A
I_{DM}	Drain Current Pulsed (Note1)	9.5*	A
V_{GS}	Gate to Source Voltage	±30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	140	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)	2.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Total Power Dissipation(@Tc=25°C)	23	W
	Derating Factor above 25°C	0.18	W/°C
T_J, T_{stg}	Junction and Storage Temperature	-55~150	°C
T_L	Channel Temperature	300	°C

*Drain current limited by junction temperature

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R_{QJC}	Thermal Resistance, Junction-to-Case	-	-	5.5	°C/W
R_{QJA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	°C/W

Electrical Characteristics (Tc = 25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit	
Gate leakage current	I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA	
Gate-source breakdown voltage	V _{(BR)GSS}	I _G = ±10 μA, V _{DS} = 0 V	±30	-	-	V	
Drain cut-off current	I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	-	-	10	μA	
		V _{DS} = 480 V, T _c = 125°C	-	-	100	μA	
Drain-source breakdown voltage	V _{(BR)DSS}	I _D = 250 μA, V _{GS} = 0 V	600	-	-	V	
Gate threshold voltage	V _{GS(th)}	V _{DS} = 10 V, I _D = 250 μA	2	-	4	V	
Drain-source ON resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 0.8A	-	4.3	5	Ω	
Forward Transconductance	g _{fs}	V _{DS} = 50 V, I _D = 0.8A	-	2.0	-	S	
Input capacitance	C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	-	270	350	pF	
Reverse transfer capacitance	C _{rss}		-	6	8		
Output capacitance	C _{oss}		-	40	50		
Switching time	Rise time	t _r	V _{DD} = 300 V, I _D = 2.0 A R _G = 25 Ω (Note4,5)	-	10	30	ns
	Turn-on time	t _{on}		-	25	60	
	Fall time	t _f		-	20	50	
	Turn-off time	t _{off}		-	25	60	
Total gate charge (gate-source plus gate-drain)	Q _g	V _{DD} = 320 V, V _{GS} = 10 V, I _D = 6.5 A (Note4,5)	-	9.0	11	nC	
Gate-source charge	Q _{gs}		-	1.6	-		
Gate-drain ("miller") Charge	Q _{gd}		-	4.3	-		

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I _{DR}	-	-	-	2.0	A
Pulse drain reverse current	I _{DRP}	-	-	-	9.5	A
Forward voltage (diode)	V _{DSF}	I _{DR} = 2 A, V _{GS} = 0 V	-	-	1.4	V
Reverse recovery time	t _{rr}	I _{DR} = 2.0A, V _{GS} = 0 V, dI _{DR} / dt = 100 A / μs	-	180	-	ns
Reverse recovery charge	Q _{rr}		-	0.72	-	μC

- Note 1.Repeatability rating :pulse width limited by junction temperature
2.L=18.5mH,I_{AS}=2.0A,V_{DD}=50V,R_G=0Ω,Starting T_J=25°C
3.I_{SD}≤2.0A,di/dt≤200A/us, V_{DD}<BV_{DSS},STARTING T_J=25°C
4.Pulse Test: Pulse Width≤300us,Duty Cycle≤2%
5.Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

Please handle with caution



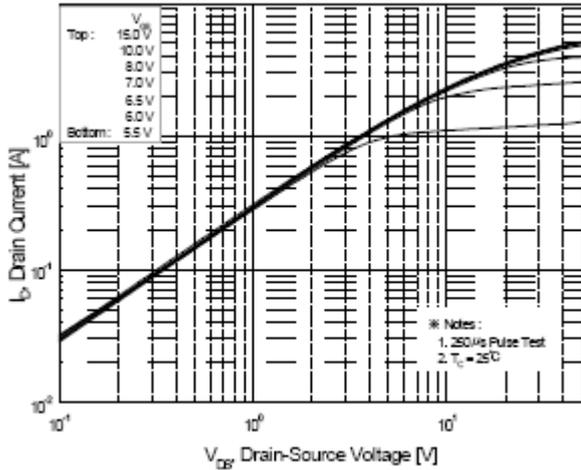


Fig. 1 On-State Characteristics

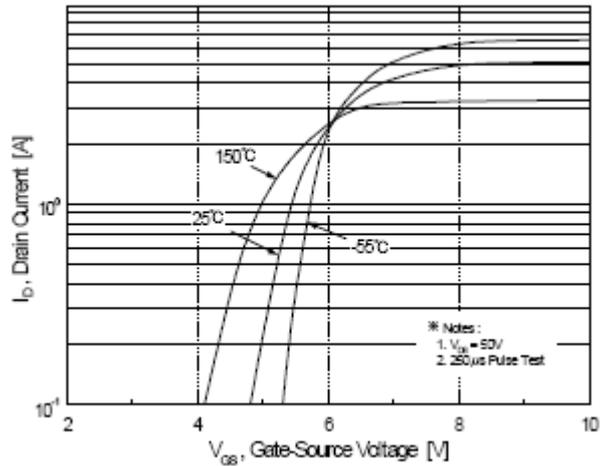


Fig. 2 Transfer Current Characteristics

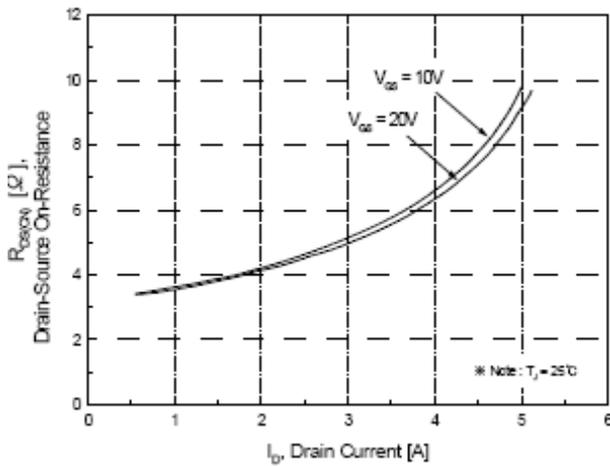


Fig. 3 On-Resistance Variation vs Drain Current

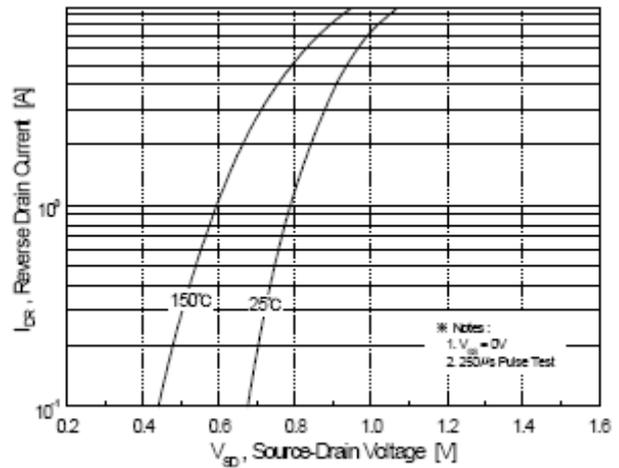


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

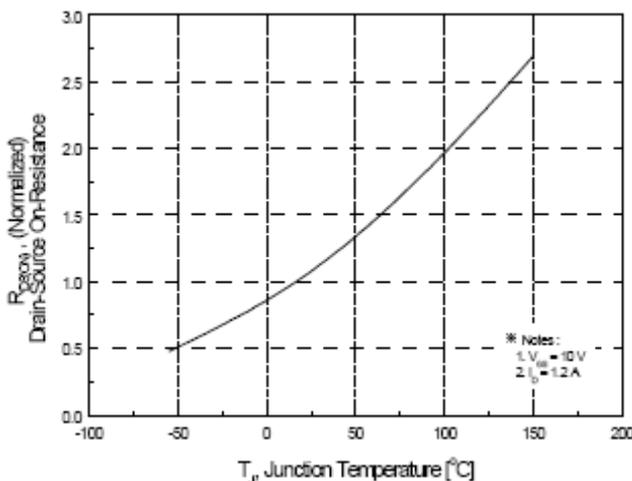


Fig. 5 On-Resistance Variation vs Junction Temperature

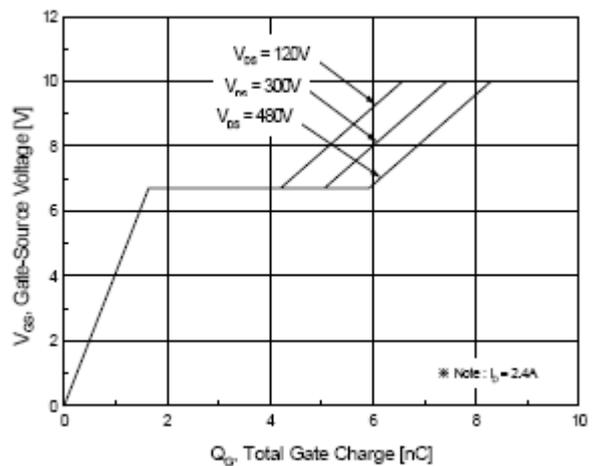


Fig. 6 Gate Charge Characteristics

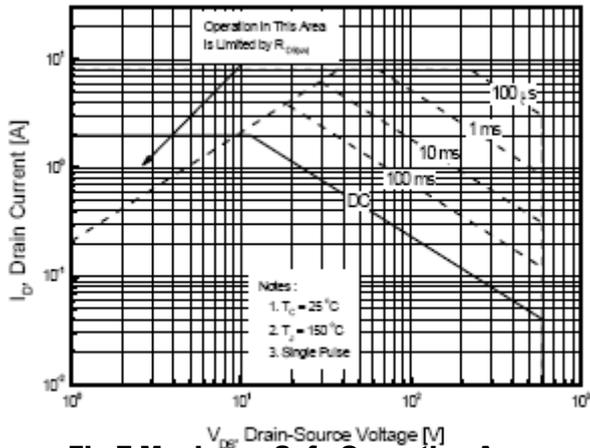


Fig.7 Maximum Safe Operation Area

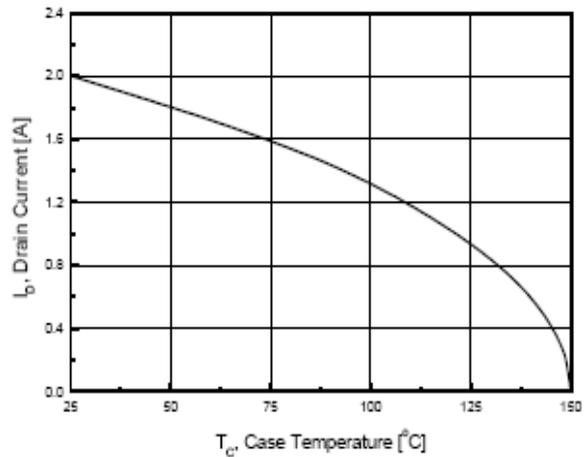


Fig.8 Maximum Drain Current vs Case Temperature

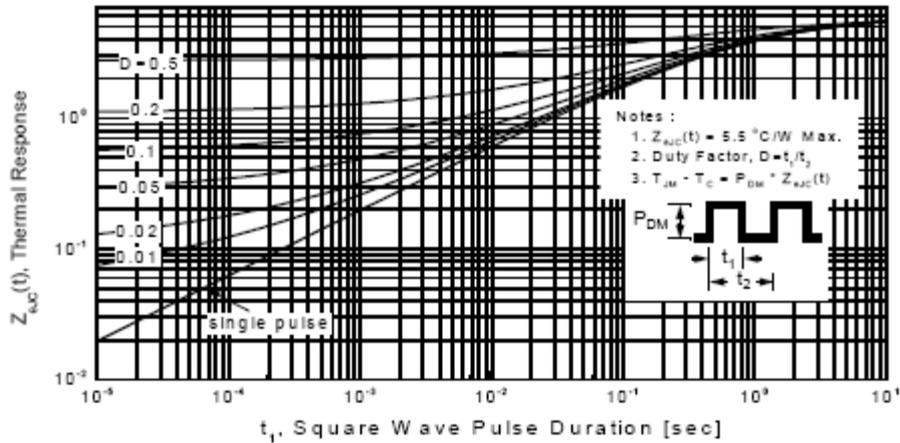


Fig.9 Transient Thermal Response Curve

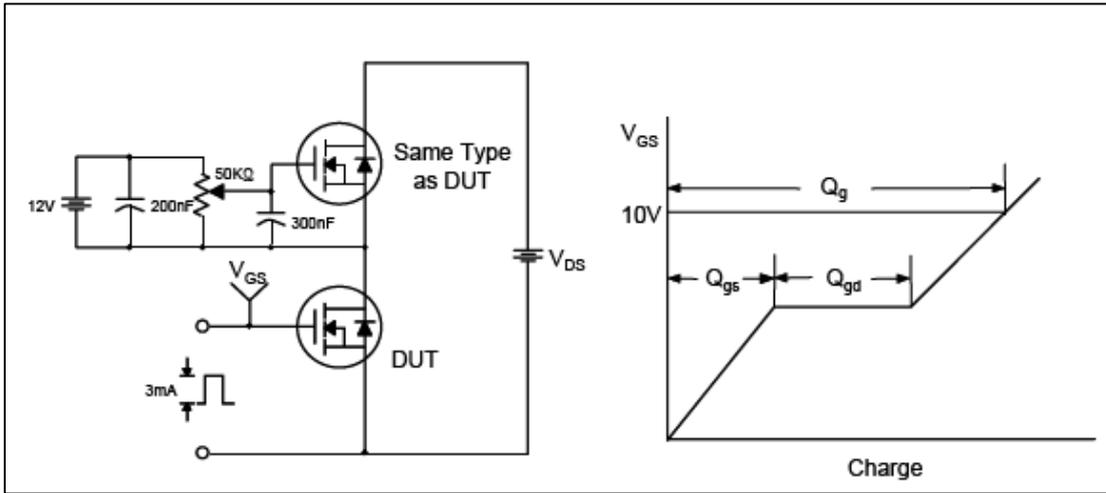


Fig.10 Gate Test Circuit & Waveform

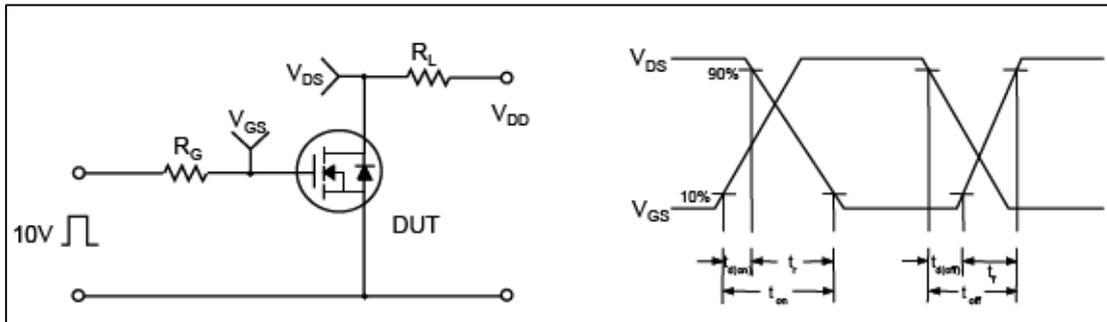


Fig.11 Resistive Switching Test Circuit & Waveform

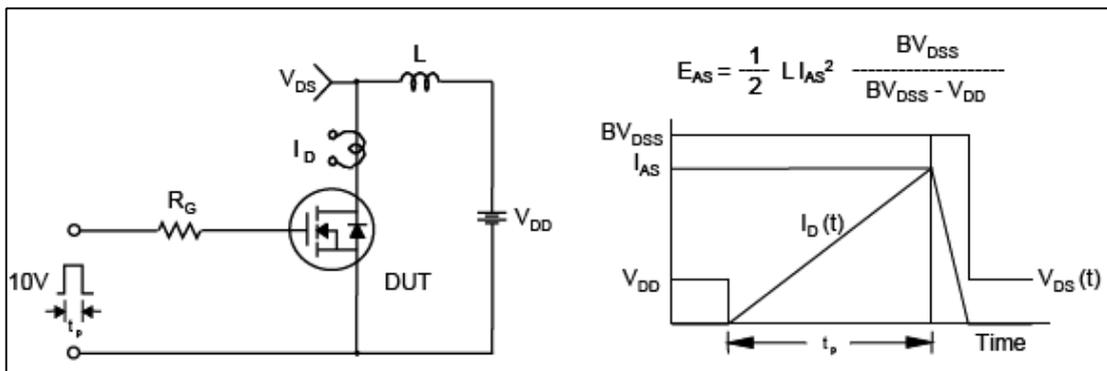


Fig.12 Unclamped Inductive Switching Test Circuit & Waveform

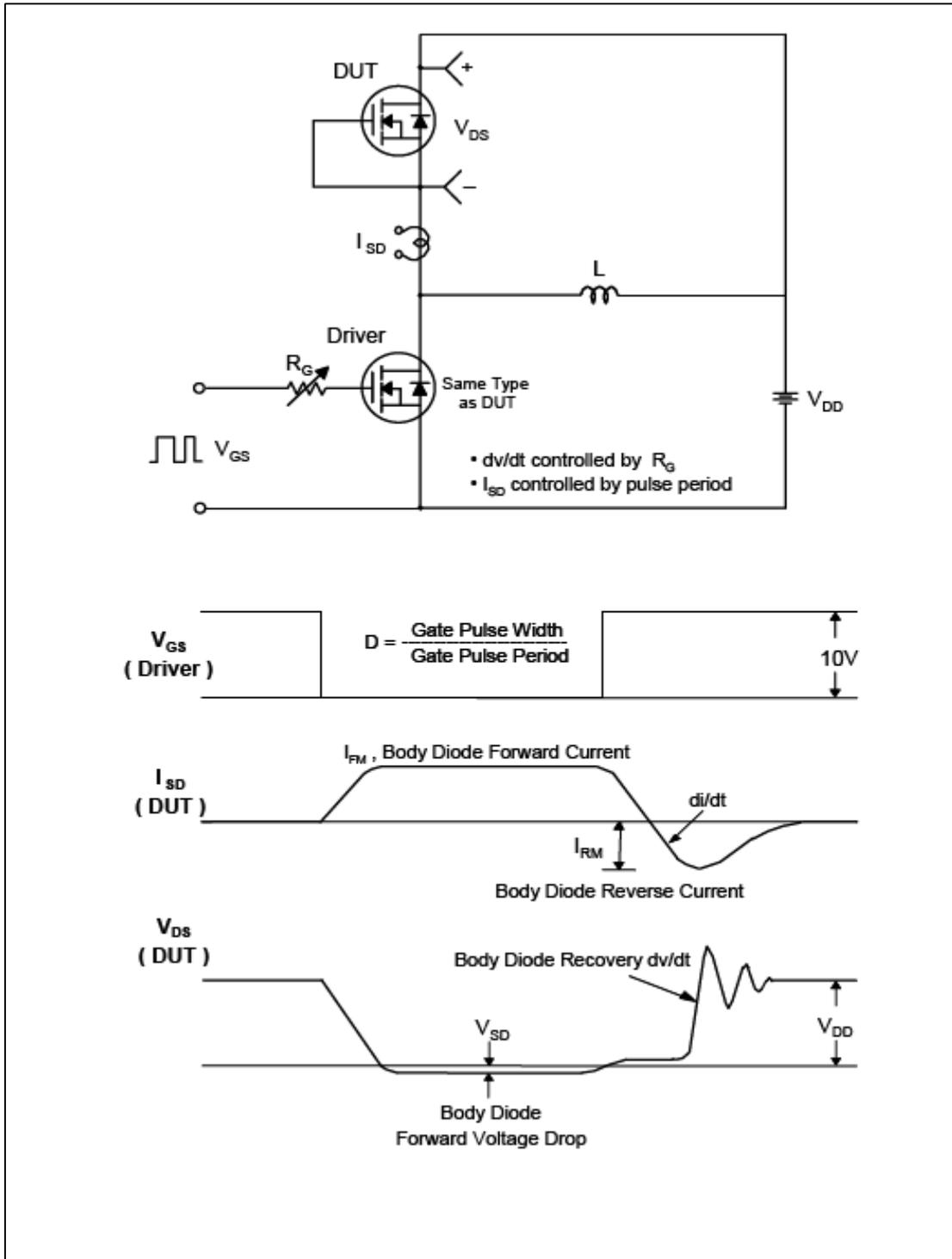


Fig.13 Peak Diode Recovery dv/dt Test Circuit & Waveform

TO-220F Package Dimension

